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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

APPLICANTS : Victor HIGGS; Freddie YUN HENG CHIN; Michael Sweeney;
and Ian Christopher MAYES

APPLICATION NO. : PCT/GB97/02388 ✓

FILED : September 5, 1997

FOR : APPARATUS AND METHOD FOR DETECTING MICRO
DEFECTS IN SEMI-CONDUCTORS

PRELIMINARY AMENDMENT

ASSISTANT COMMISSIONER FOR PATENTS
BOX PCT
WASHINGTON, D.C. 20231

Sir:

Prior to calculating the fees pursuant to the entry into the National Phase of the above-
identified Application, please amend the claims as follows:

IN THE CLAIMS:

In Claim 3, line 1, please delete "Claims 1 or 2" and insert --Claim 1--.

In Claim 4, line 1, please delete "any proceeding";

line 1, after "claim", insert --1--.

In Claim 8, line 1, please delete "Claims 5-7" and insert --Claim 5--.

In Claim 9, line 1, please delete "Claims 5-8" and insert --Claim 5--.

In Claim 10, line 1, please delete "Claims 5-9" and insert --Claim 5--.